


<b>Search Notes</b>  	<b>Application/Control No.</b>  10600390	<b>Applicant(s)/Patent Under Reexamination</b>  CHATTERJEE ET AL.
	<b>Examiner</b>  LEON HARPER	<b>Art Unit</b>  2166

SEARCHED			
Class	Subclass	Date	Examiner
707	104.1, 100, 10, 3	6/19/09	LJH

SEARCH NOTES		
Search Notes	Date	Examiner
updated search	6/19/09	LJH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Isaac M. Woo/ Primary Examiner, Art Unit 2166
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